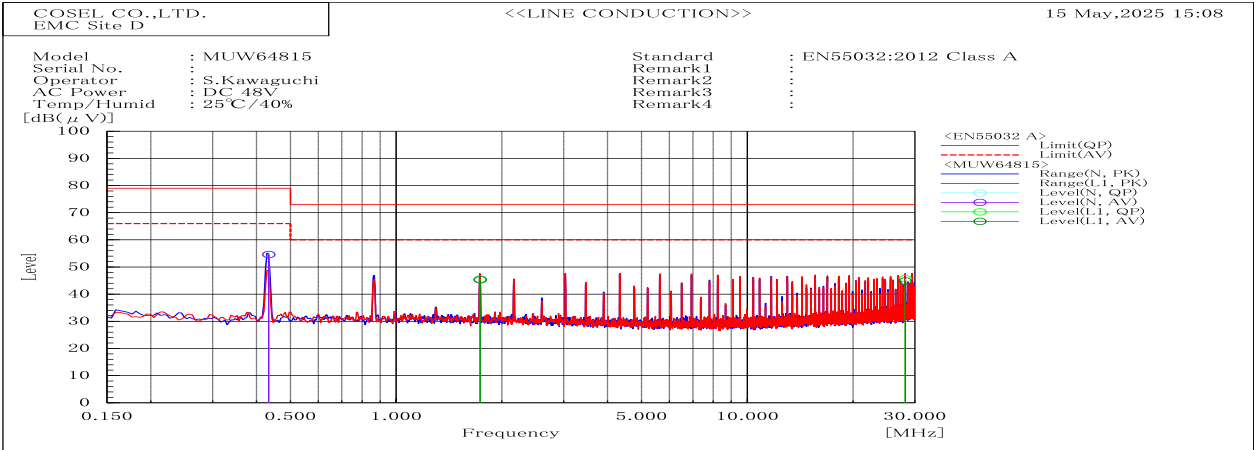
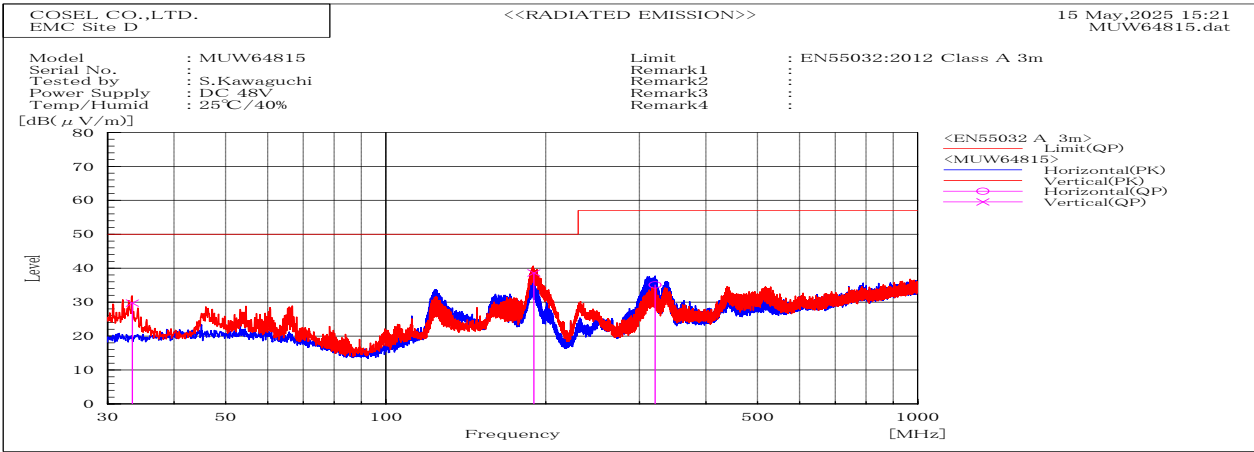


DATA SHEET		Date	15-May-25
Model	MUW64815	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi



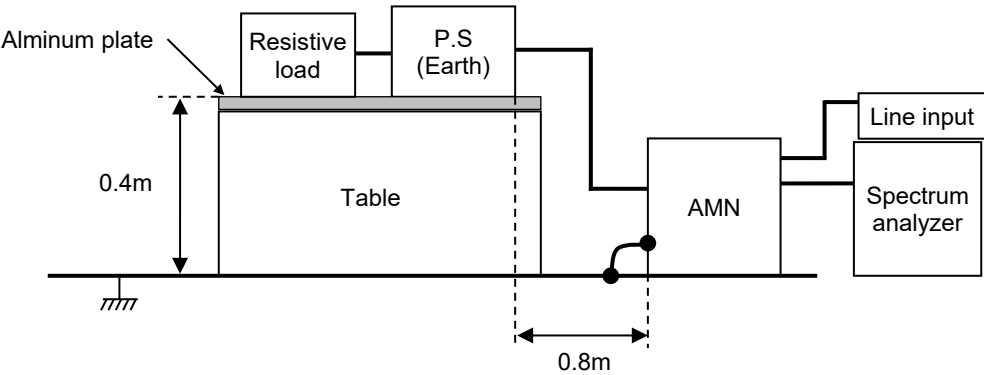
Frequency MHz	Line	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
1.735	L1	45.5	45.3	73	60	27.5	14.7	Pass	
28.193	L1	45.7	44.9	73	60	27.3	15.1	Pass	
0.434	N	54.7	54.6	79	66	24.3	11.4	Pass	



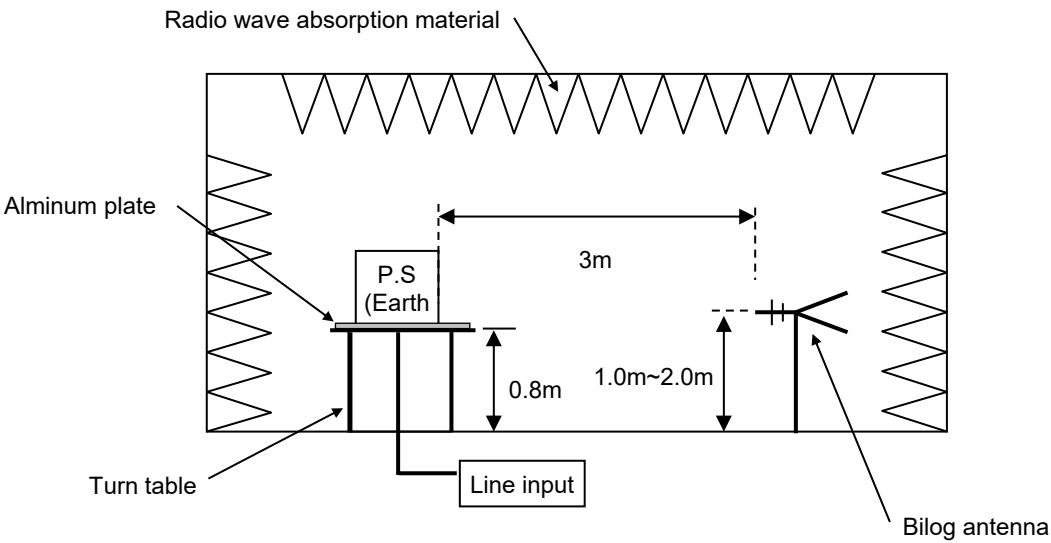
Frequency MHz	Polarization	Stability	Level dB(uV/m)	Limit dB(uV/m)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
189.93	V	Stable	38.6	50	11.4	Pass	100	350.5	
33.393	V	Stable	29.7	50	20.3	Pass	100.2	91.6	
320.937	H	Stable	35.1	57	21.9	Pass	106.3	243.4	

DATA SHEET		Date	15-May-25
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	S.Kawaguchi

1. Line conduction



2. Radiated emission

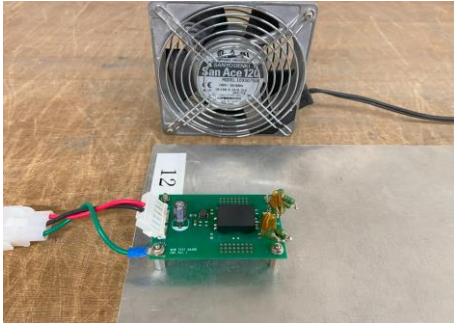


Conditions

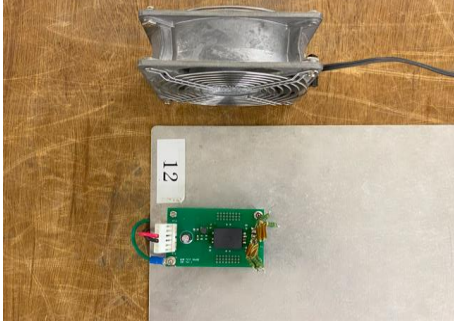
Test : EMI  
Model Name: MUW6□□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

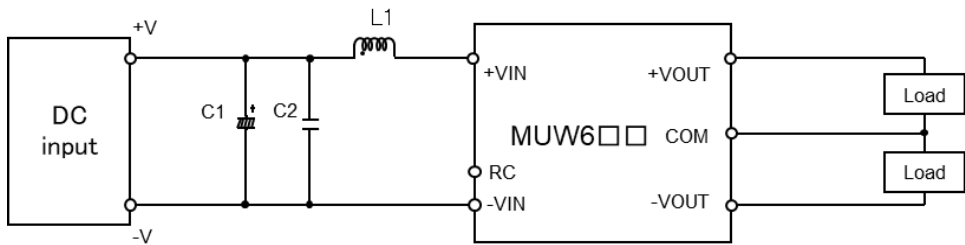


Fig.1 MUW6□□ Testing circuitry

C1 :	MUW605□	16V 220 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUW612□	50V 100 $\mu$ F	Electric capacitor (UPWseries NICHICON)
	MUW624□	—	
	MUW648□	—	
C2 :	MUW605□	16V 22 $\mu$ F	Ceramic capacitor (GRM31CC71C226M MURATA MANUFACTURING)
	MUW612□	25V 10 $\mu$ F	Ceramic capacitor (CM316X7R106K25AT KYOCERA)
	MUW624□	50V 4.7 $\mu$ F	Ceramic capacitor (GRM31CR71H475K MURATA MANUFACTURING)
	MUW648□	100V 2.2 $\mu$ F	Ceramic capacitor (C3216X7S2A225KT TDK)
L1 :	MUW605□	6500mA 1.5 $\mu$ H	Inductor(LQH5BPN1R5N38 MURATA MANUFACTURING)
	MUW612□	5000mA 2.2 $\mu$ H	Inductor(LQH5BPN2R2N38 MURATA MANUFACTURING)
	MUW624□	2600mA 10 $\mu$ H	Inductor(LQH5BPN100M38 MURATA MANUFACTURING)
	MUW648□	1600mA 22 $\mu$ H	Inductor(LQH5BPN220M38 MURATA MANUFACTURING)